

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243028US0DIV		SERIAL NO. NEW APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT 		APPLICANT Toshimitsu TETSUI, et al.					
		FILING DATE HEREWITH		GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
AA	5,226,985	07-13-93	Y-W. KIM et al.				
AB	5,558,729	09-24-96	Y-W. KIM, et al.				
AC	5,442,847	08-22-95	S.L. SEMIATIN, et al.				
AD	5,846,351	12-08-98	N. MASAHASHI, et al.				
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
AM							
AN							
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
AO	64-042539	02-14-89	JAPAN				X
AP	1-298127	12-01-89	JAPAN				X
AQ	6-049565	02-22-94	JAPAN				X
AR	6-041661	02-15-94	JAPAN				X
AS	62-000215	01-06-87	JAPAN				X
AT	4-066630	03-03-92	JAPAN				X
AU	4-124236	04-24-92	JAPAN				X
AV	6-49624	02-22-94	JAPAN				X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW	D. ZHANG et al., Intermetallics, Vol. 7, No. 10, XP-004177382, pps. 1081-1087, "Characterization of Controlled Microstructures in A TiAl (Cr, Mo, Si, B) ALLOY," October 1999.						
AX	"ASM Handbook: Vol. 3 Alloy Phase Diagrams," ASM International, 1992, p. 254.						
AY							
AZ				<input type="checkbox"/> Additional References sheet(s) attached			
Examiner				Date Considered			

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.